

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings of claims in the application:

Listing of Claims:

1. (currently amended) A method of measuring jitter in a digital signal comprising:
forming an offset reference clock signal being offset by a predetermined frequency
amount from said digital signal;
sampling said digital signal at sampling times determined by an integer multiple of the
frequency of said offset reference clock signal, such that, in the absence of jitter and said offset
by a predetermined frequency, there are a predetermined number of sampling times in each bit of
said digital signal;
detecting occasions when the number of sampling times in any bit of said digital signal is
different from said predetermined number;
counting said occasions over a predetermined time, and
deriving at least one measure of jitter from said counting of said occasions.
2. (previously presented) A method according to claim 1, wherein said offset
reference clock signal is formed by extracting a clock signal from said digital signal and
offsetting said clock signal by said predetermined frequency.
3. (previously presented) A method according to claim 2, further including
smoothing said offset reference clock signal.
4. (cancelled).
5. (currently amended) A method according to claim [[4]] 1, wherein said sampling
the times are at clock bit intervals being plus and minus one of said integer multiple.

B2
cont

6. (currently amended) A method according to claim 1, wherein the predetermined time is inversely proportional to the product of the bit rate of the digital signal and the predetermined frequency amount.

7. (previously presented) A method according to claim 1, wherein one of said at least one measure of jitter is obtained by counting up one value for each of said occasions representing sampling times greater than the predetermined number within a bit, counting down one value for each of said occasions representing sampling times less than the predetermined number within a bit and determining the difference between the maximum count value and the minimum count value.

8. (currently amended) A method according to claim 1, wherein one of said at least one measure of jitter is obtained by counting up one value for each of said occasions representing sampling times greater than the predetermined number within a bit, counting down one value for each of said occasions representing sampling times less than the predetermined number within a bit and determining the time difference between the first occasion of the maximum count value and the last occasion of the minimum count value.

9. (previously presented) A method according to claim 8, wherein the time difference is divided by said integer multiple and said predetermined time.

10. (previously presented) An apparatus for measuring jitter in a digital signal comprising:

means for forming an offset reference clock signal, which clock signal is offset by a predetermined frequency amount from said digital signal;

means for sampling said digital signal at sampling times determined by said offset reference clock signal, such that, in the absence of jitter and said offset by a predetermined frequency, there are a predetermined number of sampling items in each bit of said digital signal;

means for detecting occasions when the number of sampling times in any bit of said digital signal is different from said predetermined number; and

means for counting said occasions over a predetermined time, and

means for deriving at least one measure of jitter from said means for counting of said occasions, said deriving means comprising means for counting up one value for each of said occasions representing sampling times greater than the predetermined number within a bit and for counting down one value for each of said occasions representing sampling times less than the predetermined number within a bit and means for determining the time difference between the first occasions of the maximum count value and the last occasion of the minimum count value.

11. (previously presented) An apparatus according to claim 10, wherein said means for forming said offset reference clock signal comprises means for extracting a clock signal from said digital signal and means for offsetting the clock signal by said predetermined frequency.

B2
cont
12. (previously presented) An apparatus according to claim 11, wherein said means for forming said offset reference clock signal includes means for smoothing said offset reference clock signal.

13. (cancelled).

14. (cancelled).

15. (currently amended) An apparatus for measuring jitter in a digital signal comprising:

an offset unit arranged to form an offset reference clock signal, being offset by a predetermined frequency amount from said digital signal;

a sampler arranged to sample said digital signal at sampling times determined by said offset reference clock signal such that, in the absence of jitter and said offset by a predetermined frequency, there are a predetermined number of sampling times in each bit of said digital signal;

at least one detector arranged to detect occasions when the number of sampling items in any bit of said digital signal is different from said predetermined number;

a counter arranged to count said occasions over a predetermined time, wherein the predetermined time is inversely proportional to the product of the bit rate of the digital signal and the predetermined frequency amount, and

an analyzer arranged to derive at least one measure of jitter from said counting of said occasions.

16. (new) The apparatus according to claim 10, wherein said sampling times are determined by an integer multiple of the frequency of said offset reference clock signal.

17. (new) The apparatus of claim 15, wherein the offset reference clock signal is formed by extracting a clock signal from said digital signal and offsetting said clock signal by said predetermined frequency.

B2
cont
18. (new) The apparatus of claim 17, further including smoothing said offset reference clock signal.

19. (new) The apparatus of claim 15, wherein said sampling times are determined by an integer multiple of the frequency of said offset reference clock signal.

20. (new) The apparatus of claim 19, wherein said sampling the times are at clock bit intervals being plus and minus one of said integer multiple.

21. (new) The apparatus of claim 15, wherein one of said at least one measure of jitter is obtained by counting up one value for each of said occasions representing sampling times greater than the predetermined number within a bit, counting down one value for each of said occasions representing sampling times less than the predetermined number within a bit and determining the difference between the maximum count value and the minimum count value.

22. (new) The apparatus according to claim 19, wherein one of said at least one measure of jitter is obtained by counting up one value for each of said occasions representing sampling times greater than the predetermined number within a bit, counting down one value for each of said occasions representing sampling times less than the predetermined number within a

Appl. No. 09/674,444

PATENT

Amdt. dated May 14, 2004

Reply to Office Action of November 19, 2003

bit and determining the time difference between the first occasion of the maximum count value and the last occasion of the minimum count value.

Bg
concl 23. (new) The apparatus according to claim 22, wherein the time difference is divided by said integer multiple and said predetermined time.
